

Docket No. 245455US2/shb



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Hitoshi ISHIBASHI, et al.

SERIAL NO: 10/722,490

GAU:

FILED: November 28, 2003

EXAMINER:

FOR: ALIGNMENT PATTERN DETECTING SENSOR, METHOD OF DETERMINING ACCEPTANCE WIDTH OF THE ALIGNMENT PATTERN DETECTING SENSOR, METHOD OF FORMING ALIGNMENT PATTERN, AND IMAGE FORMING APPARATUS

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

- ☒ The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- ☐ Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

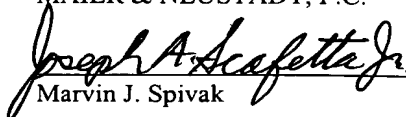
- ☐ Each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- ☐ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

- ☒ Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND,
MAIER & NEUSTADT, P.C.


Marvin J. Spivak

Registration No. 24,913

Joseph A. Scafetta, Jr.

Registration No. 26, 803

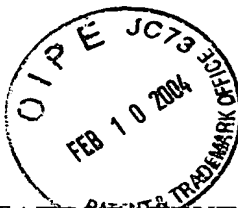
Customer Number

22850

Tel. (703) 413-3000
Fax. (703) 413-2220
(OSMMN 05/03)

DOCKET NO.: 245455US2/shb

Page 1 of 1



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Hitoshi ISHIBASHI, et al.

SERIAL NO: 10/722,490

GROUP:

FILED: November 28, 2003

EXAMINER:

FOR: ALIGNMENT PATTERN DETECTING SENSOR, METHOD OF
DETERMINING ACCEPTANCE WIDTH OF THE ALIGNMENT PATTERN
DETECTING SENSOR, METHOD OF FORMING ALIGNMENT PATTERN,
AND IMAGE FORMING APPARATUS

STATEMENT OF RELEVANCY

All of the references on Form PTO 1449 are discussed in the specification.

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTORNEY DOCKET NO.

245455US2

SERIAL NO.

10/722,490

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Hitoshi ISHIBASHI, et al.

FILING DATE

November 28, 2003

GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AO	7-19084	03/06/1995	JAPAN (with English Abstract)		X
	AP	3254244	02/04/2002	JAPAN (with English Abstract)		X
	AQ	10-329381	12/15/1998	JAPAN (with English Abstract)		X
	AR	2000-81745	03/21/2000	JAPAN (with English Abstract)		X
	AS	2001-209223	08/03/2001	JAPAN (with English Abstract)		X
	AT	2002-40746	02/06/2002	JAPAN (with English Abstract)		X
	AU	2002-229280	08/14/2002	JAPAN (with English Abstract)		X
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
	AZ	

☐ Additional References sheet(s) attached

Examiner

Date Considered

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.